

RECTANGLE TYPE LED LAMPS



LY55140/S27-PF

DATA SHEET

- DOC. NO :
 QW0905-LY55140/S27-PF

 REV.
 :
- DATE : <u>19 Sep. 2006</u>







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Absolute Maximum Ratings at Ta=25 $^\circ\!\mathrm{C}$

Deremeter	Symbol	Ratings	UNIT	
Parameter		Y		
Forward Current	lF	20	mA	
Peak Forward Current Duty 1/10@10KHz	IFP	80	mA	
Power Dissipation	PD	60	mW	
Reverse Current @5V	lr	10	μ A	
Operating Temperature	Topr	-40 ~ +85	°C	
Storage Temperature	Tstg	-40 ~ +100	°C	

Typical Electrical & Optical Characteristics (Ta=25 °C)

PART NO MATERIAL		COLOR		Peak wave length λ Pnm	$\begin{array}{c} \text{Spectral} \\ \text{halfwidth} \\ \bigtriangleup \lambda \text{ nm} \end{array}$	voltage		Luminous intensity @10mA(mcd)		Viewing angle 2 ∂ 1/2 (deg)
		Emitted	Lens			Min.	Max.	Min.	Тур.	
LY55140/S27-PF	GaAsP/GaP	Yellow	Yellow Diffused	585	35	1.7	2.6	8.0	18	138

Note : 1.The forward voltage data did not including $\pm 0.1V$ testing tolerance.

2. The luminous intensity data did not including \pm 15% testing tolerance.



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Typical Electro-Optical Characteristics Curve

Y CHIP



Fig.3 Forward Voltage vs. Temperature









Fig.4 Relative Intensity vs. Temperature



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Soldering Condition(Pb-Free)

1.Iron:

Soldering Iron:30W Max Temperature 350°C Max Soldering Time:3 Seconds Max(One time only) Distance:2mm Min(From solder joint to body)

2.Wave Soldering Profile

Dip Soldering Preheat: 120°C Max Preheat time: 60seconds Max Ramp-up 2°C/sec(max) Ramp-Down:-5°C/sec(max) Solder Bath:260°C Max Dipping Time:3 seconds Max Distance:2mm Min(From solder joint to body)



Note:1.Wave solder should not be made more than one time.2.You can just only select one of the soldering conditions as above.



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Reliability Test:

Test Item	Test Condition	Description	Reference Standard	
Operating Life Test	1.Under Room Temperature 2.If=20mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of detemining the resistance of a part in electrical and themal stressed.	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1	
High Temperature Storage Test	1.Ta=105 ℃±5℃ 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021: B-10	
Low Temperature Storage Test	1.Ta=-40 ℃±5℃ 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021: B-12	
High Temperature High Humidity Test	1.Ta=65 ℃±5℃ 2.RH=90 %~95% 3.t=240hrs ±2hrs	The purpose of this test is the resistance of the device under tropical for hours.	MIL-STD-202:103B JIS C 7021: B-11	
Thermal Shock Test	1.Ta=105 ℃±5℃ &-40℃±5℃ (10min) (10min) 2.total 10 cycles	The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011	
Solder Resistance Test	1.T.Sol=260 ℃±5℃ 2.Dwell time= 10 ±1sec.	This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1	
Solderability Test	1.T.Sol=230 ℃±5℃ 2.Dwell time=5 ±1sec	This test intended to see soldering well performed or not.	MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2	